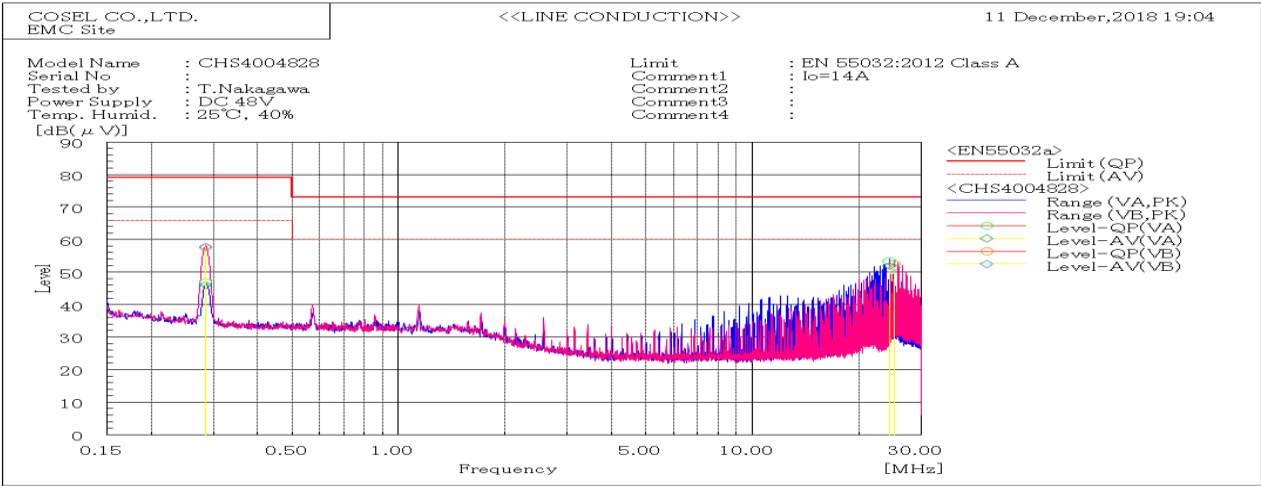
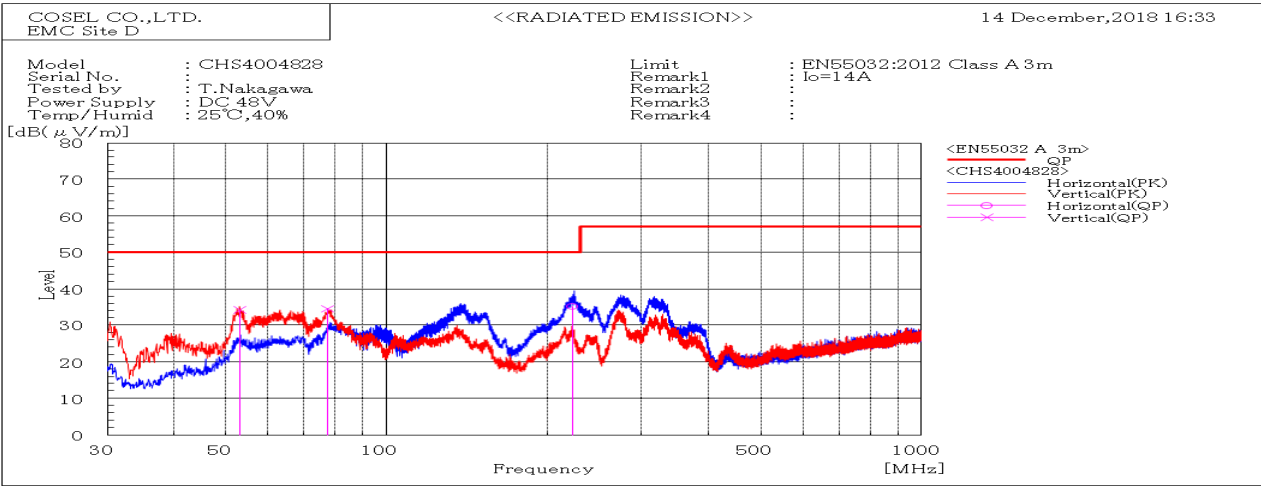


DATA SHEET		Date	19-Jan-19
Model	CHS4004828	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Nakagawa



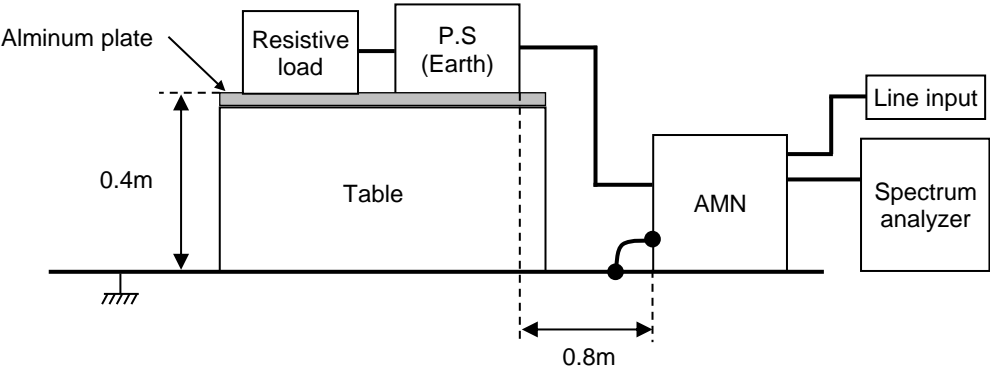
Frequency MHz	Line Phase	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.28	LA	46.9	46.0	79.0	66.0	32.1	20.0	Pass	
24.39	LA	53.3	51.9	73.0	60.0	19.7	8.1	Pass	
0.28	LB	57.6	57.8	79.0	66.0	21.4	8.2	Pass	
25.25	LB	52.6	51.5	73.0	60.0	20.4	8.5	Pass	



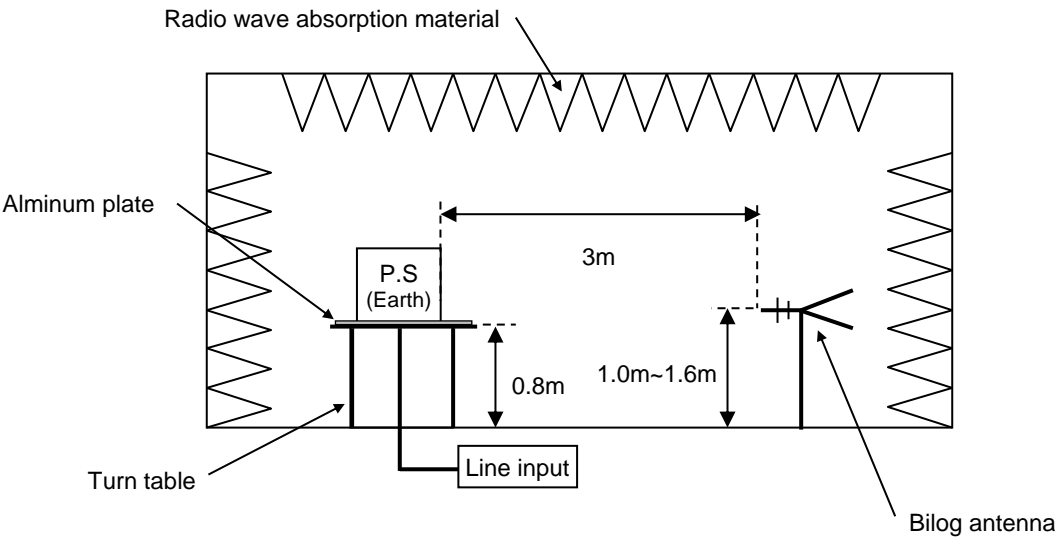
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP						
222.56	H	Stable	35.1	50.0	14.9	Pass	139.7	248.5		
53.26	V	Stable	34.2	50.0	15.8	Pass	100.0	10.0		
77.58	V	Stable	34.5	50.0	15.5	Pass	100.0	146.2		

DATA SHEET		Date	19-Jan-19
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Nakagawa

1. Line conduction



2. Radiated emission

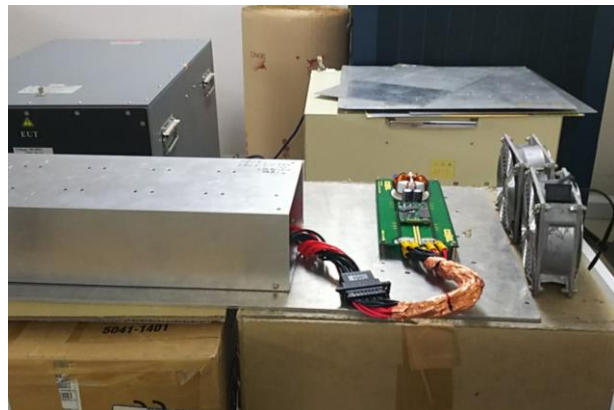


Conditions

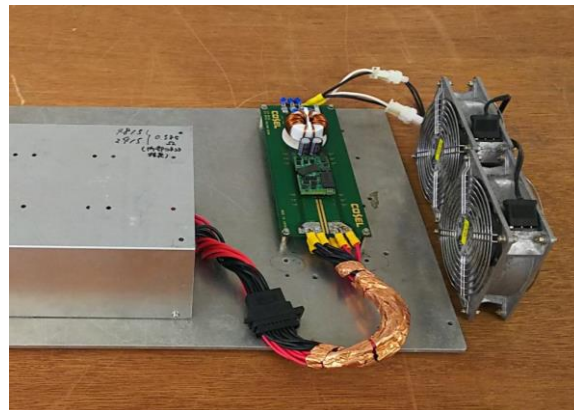
Test : EMI
Model Name : CHS40048□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

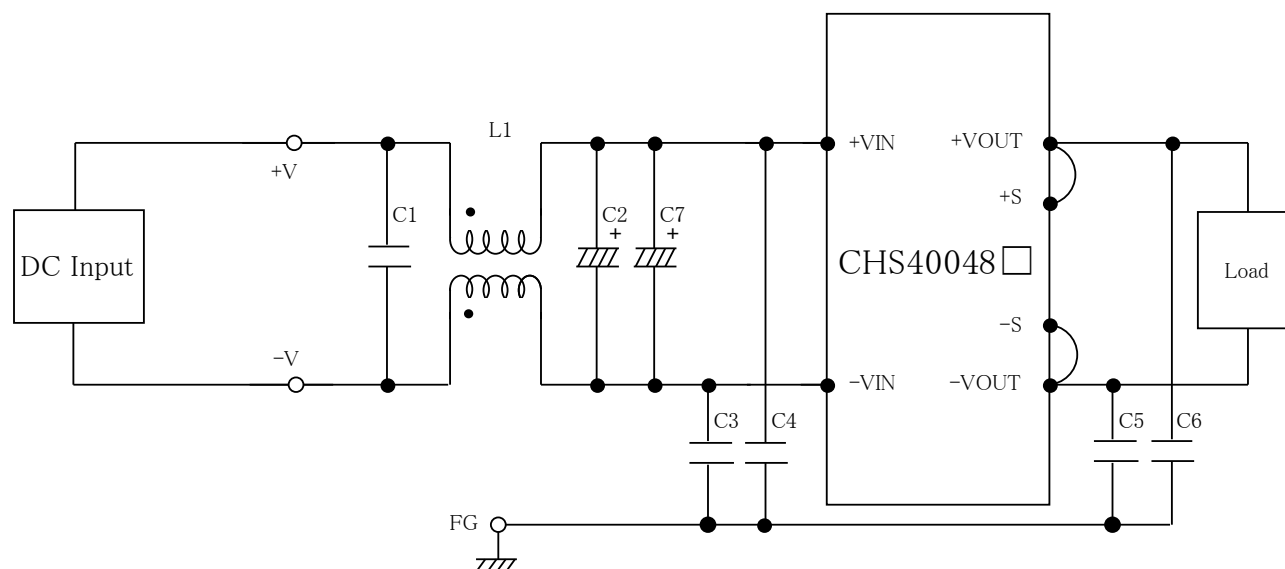


Fig.1 Testing circuitry

L1 : 1mH SC-20-10JH (TOKIN)
C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
C2,C7 : 100V 100 μ F PWseries (nichicon)
C3,C4 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
C5,C6 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)